


CORRECTION | APRIL 08 2024

## Publisher's Note: "Growth and optical performance of short-period W/Al and polished W/Si/Al/Si multilayers" [J. Appl. Phys. 134, 155301 (2023)]

D. IJpes ; A. E. Yakshin; J. M. Sturm; M. Ackermann



*J. Appl. Phys.* 135, 149901 (2024)

<https://doi.org/10.1063/5.0209743>



### Articles You May Be Interested In

Publisher's Note: "A 4th-order band-pass filter using differential readout of two in-phase actuated contour-mode resonators" [Appl. Phys. Lett. 103, 173517 (2013)]

*Appl. Phys. Lett.* (November 2013)

Erratum: "Atomic-scale planarization of 4H-SiC (0001) by combination of thermal oxidation and abrasive polishing" [Appl. Phys. Lett. 103, 111603 (2013)]

*Appl. Phys. Lett.* (October 2013)

Addendum: "Ultimate fast optical switching of a planar microcavity in the telecom wavelength range" [Appl. Phys. Lett. 98, 161114 (2011)]

*Appl. Phys. Lett.* (November 2011)



Journal of Applied Physics

## Special Topics Open for Submissions

[Learn More](#)

# Publisher's Note: "Growth and optical performance of short-period W/Al and polished W/Si/Al/Si multilayers" [J. Appl. Phys. 134, 155301 (2023)]

Cite as: J. Appl. Phys. 135, 149901 (2024); doi: [10.1063/5.0209743](https://doi.org/10.1063/5.0209743)

Submitted: 26 February 2024 ·

Published Online: 8 April 2024



View Online



Export Citation



CrossMark

D. IJpes,<sup>a)</sup> A. E. Yakshin, J. M. Sturm, and M. Ackermann

## AFFILIATIONS

Industrial Focus Group XUV Optics, MESA+ Institute for Nanotechnology, University of Twente, Enschede, The Netherlands

<sup>a)</sup>Author to whom correspondence should be addressed: [d.ijpes@utwente.nl](mailto:d.ijpes@utwente.nl)

<https://doi.org/10.1063/5.0209743>

This article was originally published online on 17 October 2023 with the figures incorrectly cited throughout the text. All online versions of this article were corrected on 13 March 2024.

28 November 2024 07:40:23